



PATENT  
Attorney Docket No. 02887.0270-00

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:	)	
	)	
Tadashi MITSUI	)	Group Art Unit: 2624
	)	
Application No.: 10/807,187	)	Examiner: David RASHID
	)	
Filed: March 24, 2004	)	
	)	
For: PATTERN MEASURING	)	Confirmation No.: 3737
APPARATUS, PATTERN	)	
MEASURING METHOD, AND	)	
MANUFACTURING METHOD OF	)	
SEMICONDUCTOR DEVICE	)	

**Mail Stop RCE**  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

**AMENDMENT**

This Amendment is being filed concurrently with a Request for Continued Examination under 37 C.F.R. § 1.114, and in reply to the final Office Action mailed September 7, 2007, the period for response to which extends through December 7, 2007. Applicant respectfully requests reconsideration of this application in view of the following amendments and remarks.